PATENT ABSTRACTS OF JAPAN

(11)Publication number :　　　64-010108

(43)Date of publication of application : 13.01.1989

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(51)Int.Cl.　　　　　　　　　　　G01B 11/00
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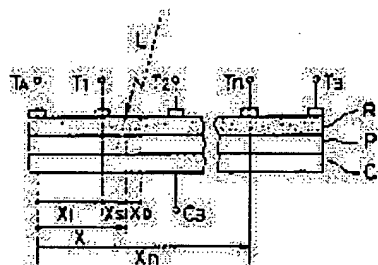
(22)Date of filing :　　　02.07.1987　　(72)Inventor : IDESAWA MASANORI

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(54) CONSTITUTION OF SEMICONDUCTOR IMAGE POSITION DETECTING ELEMENT AND IMAGE POSITION DETECTING METHOD

(57)Abstract:

PURPOSE: To detect an image position with high accuracy by dividing the detection area of a semiconductor image position detecting element into plural sections, and selecting an output electrode provided at a border part and putting an optional section in operation as one element.

CONSTITUTION: When light L is incident on between output electrodes T1 and T2, output electrodes TA and TB are selected, the light incidence position X is found from the output currents of them, and then the light incidence position X is obtained with position accuracy obtained by dividing the interval between the output electrodes TA and TB by the resolution of an A/D converter, thereby determining the section including the light incidence position. Further, an output electrode with minimum section width including the light incidence position is selected and the light incidence position XD in the selected section is found from the output current of the selected output electrode; and then the light incidence position XD in the selected section is determined with position accuracy obtained by dividing the selected section by the resolution of the A/D converter and XD is added to the position X1 of the output electrode T1 to determine the light incidence position on the whole.

LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision